

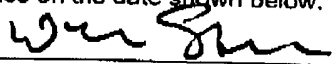
Docket No.: P2001,0356

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I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 or facsimile transmitted to the U.S. Patent and Trademark Office on the date shown below.

  
Werner H. StemerDate February 15, 2007IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applic. No.	:	10/715,073	Confirmation No: 3310
Applicant	:	Torsten Seidel et al.	
Filed	:	November 17, 2003	
Title	:	CONFIGURATION AND METHOD FOR DETECTING DEFECTS ON A SUBSTRATE IN A PROCESSING TOOL	
Art Unit	:	2624	
Examiner	:	Samir A. Ahmed	
Docket No.	:	P2001,0356	
Customer No.	:	24131	

R E S P O N S E

Hon. Commissioner for Patents


Sir:

Responsive to the Office Action dated January 24, 2007, the following remarks are made:

In deference to the restriction requirement on pages 2 and 3 of the above-identified Office Action, applicants elect Group III, claims 9-14, drawn to a method for detecting defects on a semiconductor device, classified in class 382, subclass 149, for prosecution at this time.

In view of the foregoing, the early issuance of an Action on the merits of claims 9-14 is solicited.

Respectfully submitted,

  
Werner H. Stemer (34,956)

Date: February 15, 2007

Lerner Greenberg Stemer LLP  
Post Office Box 2480  
Hollywood, FL 33022-2480  
Tel: (954) 925-1100  
Fax: (954) 925-1101  
/bh